

Docket No. 49959-145

PATENT

NOV 07 2003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Daniel I SOME, et al.

Serial No.: 09/784,626

Filed: February 14, 2001

: Response Under 37 CFR 1.116 - Expedited Procedure
Customer Number: 20277

: Confirmation Number: 3092

: Group Art Unit: 2882

: Examiner: Hoon K. Song

For: LASER SCANNING WAFER INSPECTION USING NONLINEAR OPTICAL PHENOMENA

Box AFMail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Transmitted herewith is an Amendment in the above-identified application.

No additional fee is required.
 Applicant is entitled to small entity status under 37 CFR 1.27
 Also attached:

The fee has been calculated as shown below:

	NO. OF CLAIMS	HIGHEST PREVIOUSLY PAID FOR	EXTRA CLAIMS	RATE	FEE
Total Claims	32	34	0	\$18.00 =	\$0.00
Independent Claims	4	3	1	\$86.00 =	\$86.00
Multiple claims newly presented					\$0.00
Fee for extension of time					\$0.00
					\$0.00
Total of Above Calculations					\$86.00

Please charge my Deposit Account No. 500417 in the amount of \$86.00. An additional copy of this transmittal sheet is submitted herewith.

The Commissioner is hereby authorized to charge payment of any fees associated with this communication or credit any overpayment, to Deposit Account No. 500417, including any filing fees under 37 CFR 1.16 for presentation of extra claims and any patent application processing fees under 37 CFR 1.17.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

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Date: November 7, 2003

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: **RESPONSE UNDER 37 CFR 1.116**
: **EXPEDITED PROCEDURE**

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AMENDMENT UNDER 37 CFR 1.116

Mail Stop Not sure yet
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The following Amendment and Remarks are submitted in response to the Final Office
Action mailed September 17, 2003. Please amend the above-identified application as follows.

11/10/2003 JBALINAN 0000032 500417 09784626
01 FC:1201 86.00 DA